Notice of References Cited Application/Control No. 10/790,752 Examiner David J. Makiya Applicant(s)/Patent Under Reexamination ZIRK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,771,588 A	06-1998	Petrich, Richard F.	30/308.2
	В	US-			
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	F	US-			
	G	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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